



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Jiping Li; Peter G. Borden; Edgar B. Genio
Assignee: Applied Materials, Inc.
Title: High Throughput Measurement Of Via Defects In Interconnects
Serial No.: 10/813,407 Filing Date: March 29, 2004
Examiner: Trinh, Michael Manh Group Art Unit: 2822
Docket No.: BOX016 US Confirmation No: 5642

Santa Clara, California
September 6, 2005

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, §1.97 and §1.98, the Applicants submit for consideration in the above-identified patent application the documents listed on the accompanying Form PTO-1449. Copies of documents numbered 121-125 are also submitted herewith. The remaining documents are not attached hereto, because these documents are issued patents or publications which are readily available in the U.S. Patent and Trademark Office. The Examiner is requested to make all of the listed documents of record. Applicants would appreciate the Examiner initialing and returning the Form PTO-1449, indicating that the information has been considered and made of record herein.

Item 125 identified in the attached PTO-1449 is a partial International Search Report (ISR) in a PCT application which claims priority from the current application. Note also that the attached partial ISR (item 125) cites items 113-115 in the attached PTO-1449 and item 19 in an earlier PTO-1449 filed on March 25, 2005. In that earlier PTO-1449 Applicants also listed two prosecution histories as items 97 and 101, which contain the two items marked "X" in the attached partial ISR (item 125).

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This Information Disclosure Statement is submitted after receipt of a restriction requirement but before a first Office Action on the merits. Accordingly, no fee should be required. If a fee is required, please charge the deposit account 50-2263 and identify the charge by using the docket number BOX016 US.

The information contained in this Supplemental Information Disclosure Statement is to the best of my knowledge and is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

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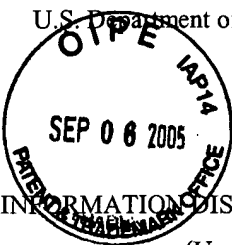
Respectfully submitted,



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 <p>U.S. Department of Commerce, Patent and Trademark Office</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p>(Use several sheets if necessary)</p>	Application No.:	10/813,407
	Filing Date:	March 29, 2004
	First Named Inventor:	Jiping Li
	Group Art Unit:	2822
	Examiner Name:	Trinh
	Confirmation No.:	5642
	Attorney Docket No.:	BOX016 US

U.S. Patent Documents							
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	107	6,040,936	3/21/01	Kim et al.	359	245	
	108	6,720,248	4/13/04	Ryo	438	622	
	109	6,747,355	6/8/04	Abiru	257	758	
	110	4,873,434	10/10/89	See et al.	250	235	
	111	6,541,747 B1	4/1/03	Kikuchi et al.	250	201	
	112	2002/0167326 A1	11/14/02	Borden et al.	324	752	
	113	2003/0165178 A1	9/4/03	Borden et al.	374	5	
	114	6,387,715	5/14/02	David et al.	438	16	
	115	2001/0017878 A1	8/30/01	Nozoe et al.	374	7	
	116	6,330,361	12/11/01	Mitchell et al.	382	211	
	117	4,201,087	5/6/80	Akita et al.	73	339	
	118	6,178,020	1/23/01	Schultz et al.	359	107	
	119	5,128,864	7/7/92	Waggener et al.	364	413	
	120	5,304,931	4/19/94	Flamig et al.	324	309	
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)							
	121	J.M. Ziman, F.R.S., "Principles of the Theory of Solids", 2nd Edition, Cambridge At the University Press 1972, pp 278-282					
	122	Chung Wah See and Mehdi Vaez-Iravani, "Differential amplitude scanning optical microscope: theory and applications", Applied Optics Vol. 27, No. 13, July 1, 1988, pp 2786-2792					
	123	International Search Report in PCT/US03/06250 which claims priority of US Application 10/090,287					
	124	Written Opinion in PCT/US99/12999 which claims priority of US Application 09/095,805					
	125	Communication Relating To Results of Partial International Search in PCT/US05/009588, which claims priority of US Application 10/813,407 (<i>current application</i>)					

Examiner:	Date Considered:
<p>* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.</p>	